

Notice of References Cited	Application/Control No. 10/780,888		Applicant(s)/Patent Under Reexamination INOUE ET AL.	
	Examiner Maria N. Von Buhr		Art Unit 2125	Pag 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0174130 A1	09-2004	Inoue et al.	318/569
*	B	US-2002/0013639 A1	01-2002	Fujishima et al.	700/175
*	C	US-6,615,103 B2	09-2003	Fujishima et al.	700/175
*	D	US-6,384,560 B1	05-2002	Kakino et al.	318/566
*	E	US-6,129,609 A	10-2000	Ripper et al.	451/8
*	F	US-5,857,166 A	01-1999	Kim, Nam H.	702/179
*	G	US-5,568,028 A	10-1996	Uchiyama et al.	318/566
*	H	US-4,536,849 A	08-1985	Borisch et al.	702/42
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	EP 1449615 A1	08-2004	EPO	Inoue et al.	---/---
*	O	JP 07-108443 A	04-1995	Japan	Uchiyama et al.	---/---
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.